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invited speaker series

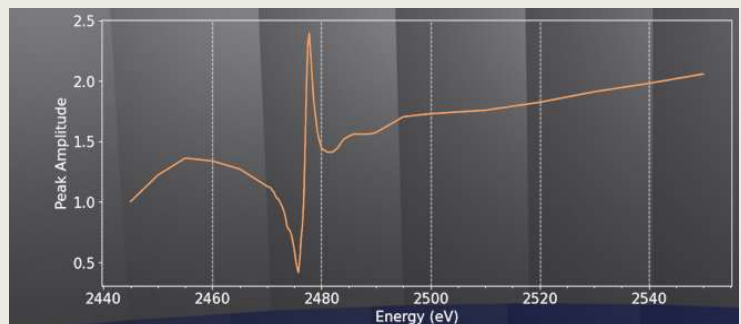
Microstructure characterization using resonant scattering*

Resonant scattering offers enhanced microstructure determination of organic semiconductors, which are often restricted by a lack of diffraction peaks. I explore tender-resonant x-ray scattering (T-ReXS) in the context of grazing incidence wide-angle-x-ray-scattering (GI-WAXS) measurements on the organic semiconductor P3HT. I also share professional, open-source, computational toolkits I have developed for this work and related experiments.

Date: Wednesday, 1st Oct 2025

Time: 3 pm

Room: S 135 (NW III)



*Dr. Matt Gebert
Monash University
Australia*